

## 800V 10A N-Channel Enhancement Mode Power MOSFET

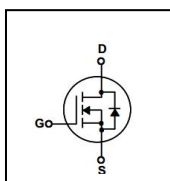
### General Description

BXP10N80 is Bridgelux high voltage MOSFET family based on advanced planar DMOS technology. This advanced MOSFET family has optimized on-state resistance, and also provides superior switching performance and higher avalanche energy strength. This device family is suitable for high efficiency switch mode power supplies.

### FEATURES

- $R_{DS(on)} \leq 1 \Omega$  @  $V_{GS}=10V$ ,  $I_D=5A$
- Excellent  $R_{DS(on)}$  and Low Gate Charge
- Fast switching capability
- Lead free product is acquired

### SYMBOL



TO-220



TO-220F

### ASSEMBLY MESSAGE

Product Name	Package	Packaging
BXP10N80P	TO-220	Tube
BXP10N80F	TO-220F	Tube

### ABSOLUTE MAXIMUM RATINGS ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Parameter		Symbol	Rating		Unit
			BXP10N80P	BXP10N80F	
Drain-Source Voltage		$V_{DSS}$	800		V
Drain Current	Continuous ( $T_C = 25^\circ\text{C}$ )	$I_D$	10		A
	Continuous ( $T_C = 100^\circ\text{C}$ )		6.4		A
Drain Current	Pulsed (Note1)	$I_{DM}$	40		A
Gate-Source Voltage		$V_{GSS}$	$\pm 30$		V
Avalanche Energy	Single Pulse (Note2)	$E_{AS}$	953		mJ
Avalanche Current (Note1)		$I_{AR}$	2.8		A
Peak Diode Recovery $dv/dt$ (Note3)		$dv/dt$	5		V/ns
Power Dissipation (Note 2)	$T_C = 25^\circ\text{C}$	$P_D$	156	44	W
	Derate above $25^\circ\text{C}$		1.248	0.352	W/ $^\circ\text{C}$
Maximum Junction Temperature		$T_J$	150		$^\circ\text{C}$
Storage Temperature Range		$T_{STG}$	-55 to 150		$^\circ\text{C}$

- Note:**
1. Repetitive Rating: Pulse width limited by maximum junction temperature
  2.  $L=20\text{mH}$ ,  $V_{DD}=50\text{V}$ ,  $R_G=25 \Omega$ , Starting  $T_J = 25^\circ\text{C}$
  3.  $I_{SD} \leq 10.0\text{A}$ ,  $di/dt \leq 100\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$

## THERMAL CHARACTERISTICS

Parameter	Symbol	Max.		Unit
		BXP10N80P	BXP10N80F	
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.8	2.83	°C / W
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	62.5	°C / W

## ELECTRICAL CHARACTERISTICS (T<sub>J</sub>=25°C, unless otherwise Noted)

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	VGS=0V, ID=250μA	800			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	VDS=800V, VGS=0V			1	uA
		VDS=640V, TC = 125°C			100	uA
Gate-Body Leakage Current, Forward	I <sub>GSS</sub>	VGS=30V			100	nA
Gate-Body Leakage Current, Reverse		VGS=-30V			-100	nA
Breakdown Voltage Temperature Coefficient	ΔBVDSS/ ΔTJ	ID = 250 μA		0.5		V/°C
ON CHARACTERISTICS						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	VDS=VGS, ID=250μA	3		4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	VGS=10V, ID=5A		0.8	1	Ω
Forward Trans conductance (Note4)	g <sub>FS</sub>	VDS = 15V, ID=10A		20		S
DYNAMIC PARAMETERS						
Input Capacitance	C <sub>ISS</sub>	VDS=25V, VGS=0V, f=1.0MHz		1900		pF
Output Capacitance	C <sub>OSS</sub>			220		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			55		pF
SWITCHING PARAMETERS						
Turn-ON Delay Time	t <sub>D(ON)</sub>	VDD=400V, ID=10A, VGS = 10V ,RG=25Ω (Note4,5)		41		ns
Turn-ON Rise Time	t <sub>R</sub>			20		ns
Turn-OFF Delay Time	t <sub>D(OFF)</sub>			68		ns
Turn-OFF Fall-Time	t <sub>F</sub>			35		ns
Total Gate Charge(Note5)	Q <sub>G</sub>	VDS =640V, VGS =10V, ID =10A (Note4,5)		71		nC
Gate Source Charge	Q <sub>GS</sub>			12		nC
Gate Drain Charge	Q <sub>GD</sub>			28		nC
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Drain-Source Diode Forward Voltage	V <sub>SD</sub>	IS=5A, VGS=0V			1.4	V
Diode Continuous Forward Current	I <sub>S</sub>				10	A
Pulsed Drain-Source Current	I <sub>SM</sub>				40	A
Reverse Recovery Time	t <sub>RR</sub>	VGS = 0 V, ISD = 10A		997		ns
Reverse Recovery Charge	Q <sub>RR</sub>	di/dt=100 A/μs (Note4,5)		4.6		uC

Note: 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%

5. Essentially independent of operating temperature

# TYPICAL CHARACTERISTICS

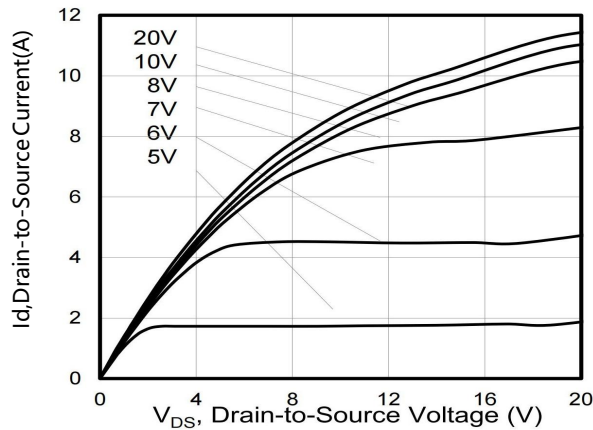


Figure1. Typical Output Characteristics

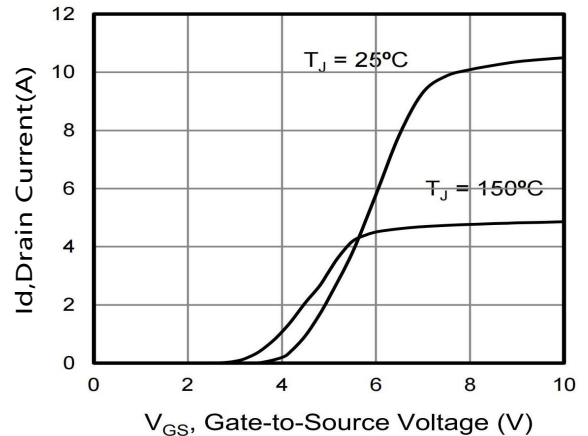


Figure2. Typical Transfer Characteristics

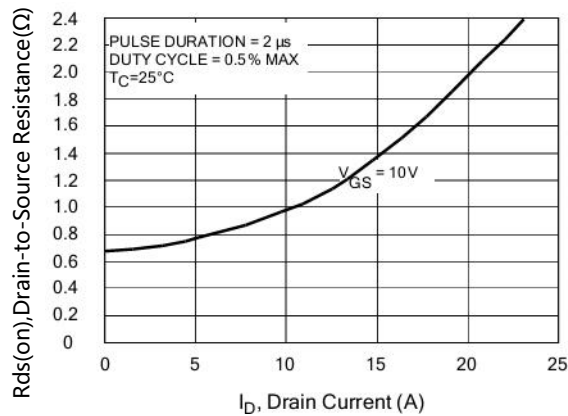


Figure3. On-Resistance versus Drain Current

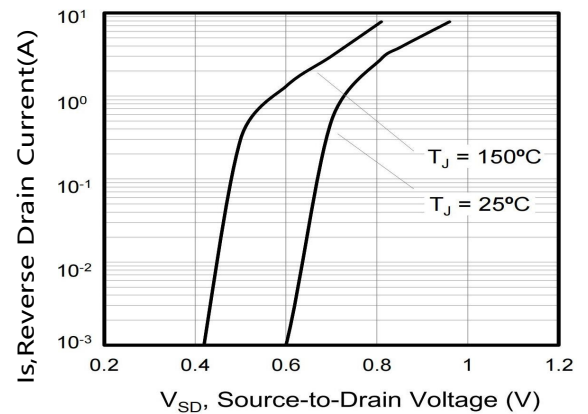


Figure4. Diode forward voltage versus Current

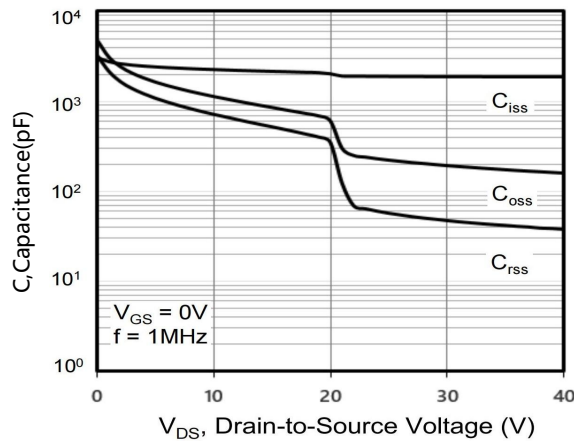


Figure5. Typical Capacitance versus  $V_{DS}$

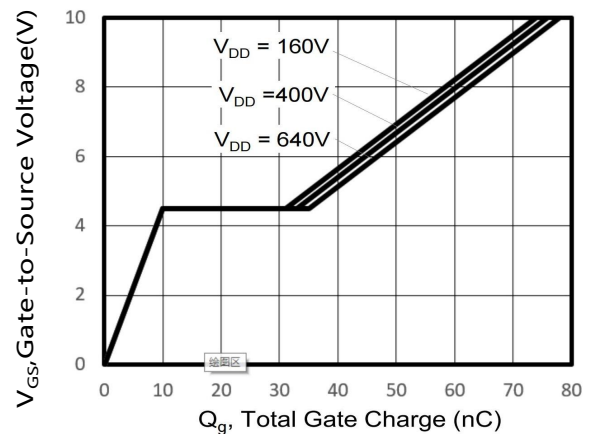


Figure6. Typical Gate Charge versus  $V_{GS}$

# TYPICAL CHARACTERISTICS(Cont.)

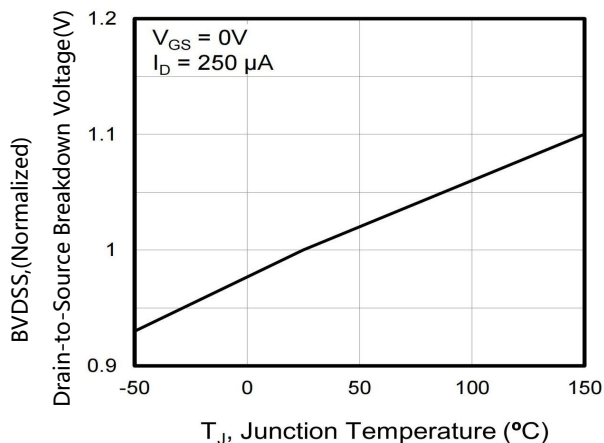


Figure7.  $BV_{DSS}$  Variation with Temperature

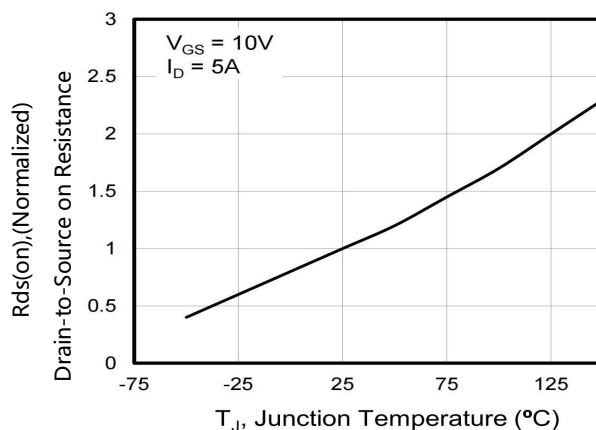


Figure8. On-Resistance Variation with Temperature

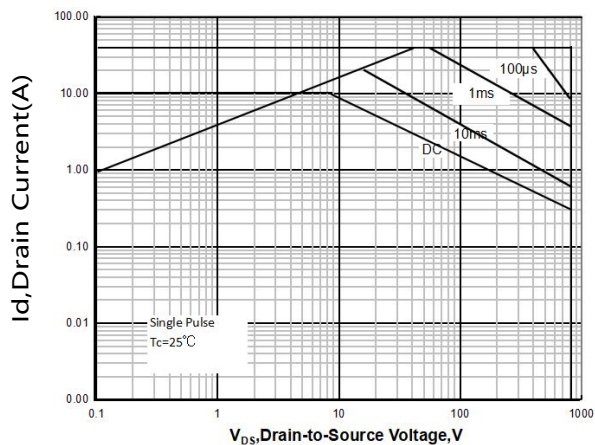


Figure9. Maximum Safe Operating Area  
BXP10N80P

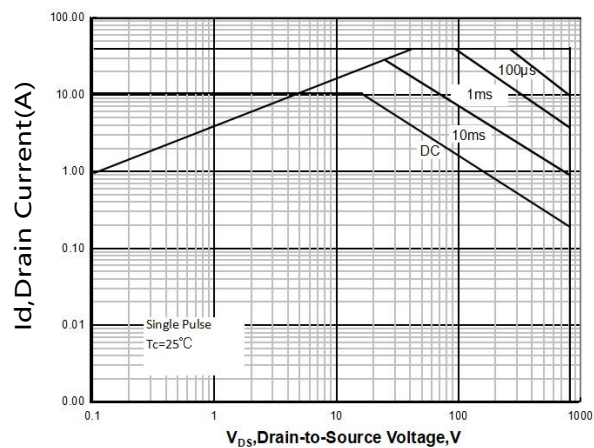


Figure9. Maximum Safe Operating Area  
BXP10N80F

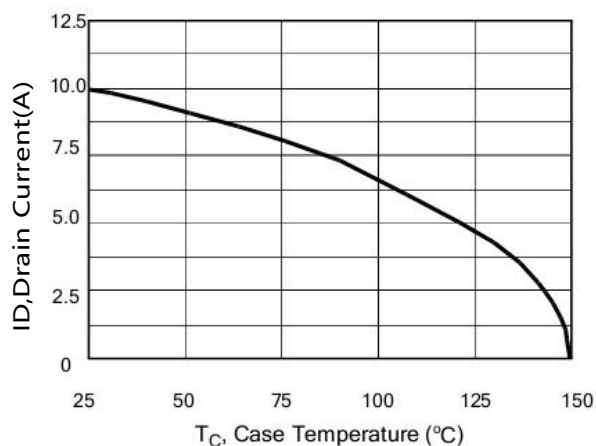
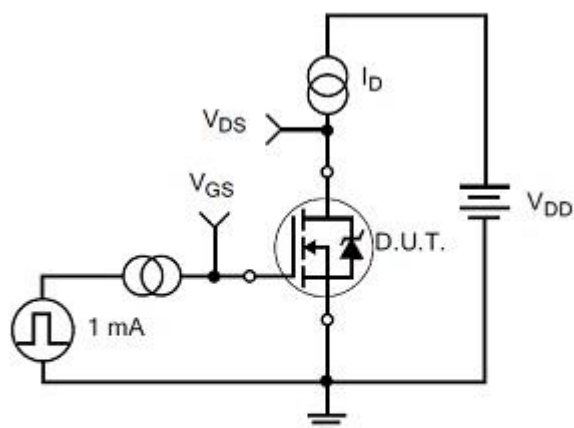
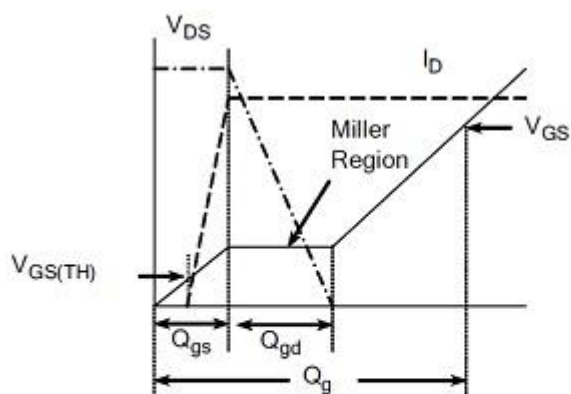


Figure10. Maximum Continuous Drain Current  
versus Case Temperature

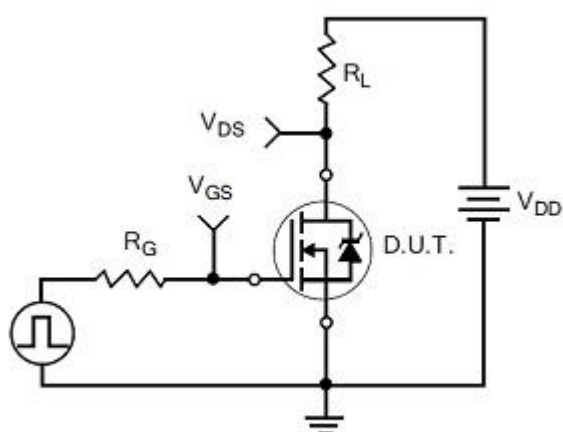
## TEST CIRCUITS AND WAVEFORMS



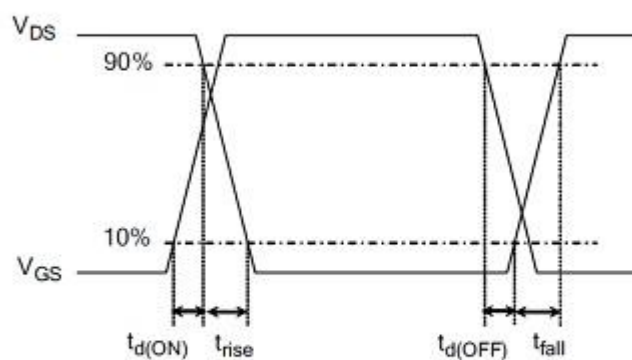
Gate Charge Test Circuit



Gate Charge Waveform

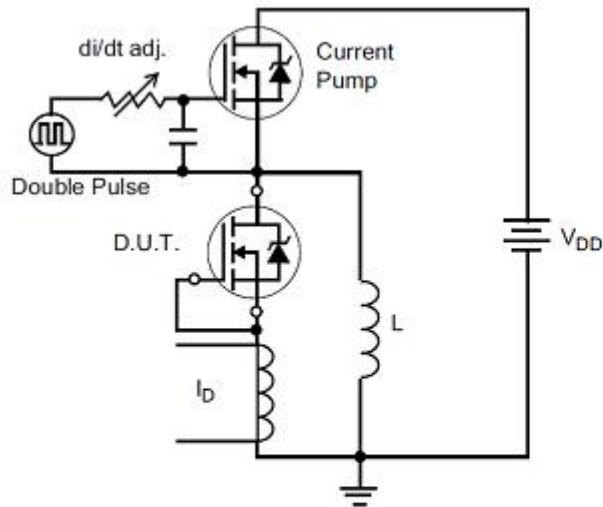


Resistive Switching Test Circuit

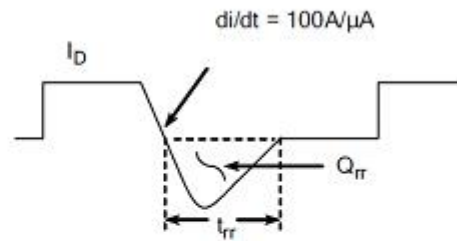


Resistive Switching Waveforms

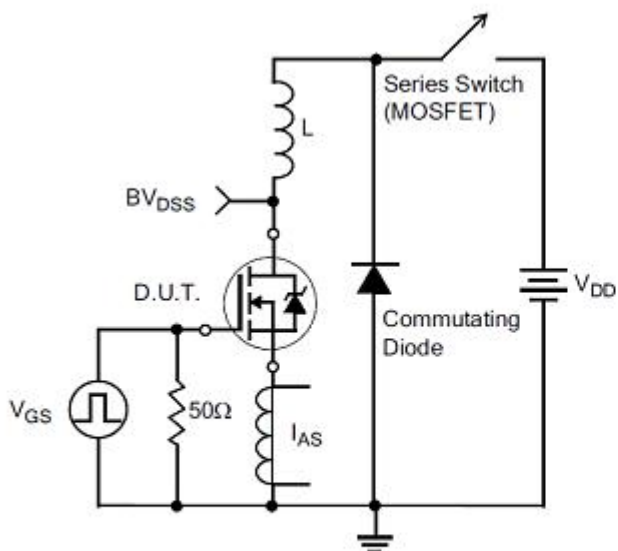
# TEST CIRCUITS AND WAVEFORMS(Cont.)



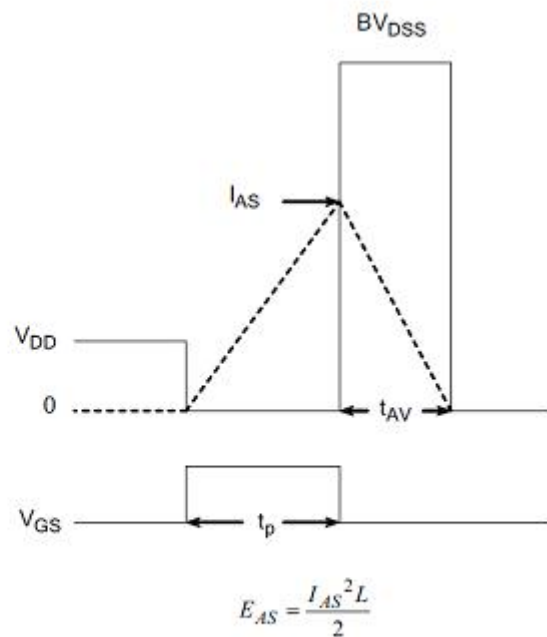
Diode Reverse Recovery Test Circuit



Diode Reverse Recovery Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

## Revision history

### Document revision history

Date	Revision	Changes
11-Oct-2021	1.0	First release
5-Jan-2022	1.1	Update parameter

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